



PRODUCT/PROCESS CHANGE NOTICE (PCN)

ATTACHMENT I - PCN # : A1406-01

PCN Type: Manufacturing Site - Alternate Assembly Locations
Data Sheet Change: None
 No change in moisture sensitivity level (MSL)

Detail Of Change:

This notification is to advise our customers that IDT is adding Amkor, Philippines (ATP) and ASE Chungli (ASECL) as alternate Assembly facilities. Presently, ATP and ASECL are qualified IDT Subcontractor.

The material set details of the current and alternate assembly locations is as shown in Table 2. The die attach and mold compound used at the alternate assembly are qualified IDT materials. There is no change from the existing qualified lead frame material, lead finish, and wire for the alternate assembly locations.

There is no change to the moisture performance.

Table 1: The Existing and Alternate Assembly Locations

Package	Existing Assembly	Alternate Assembly	
	ATK - Amkor, Korea	ATP - Amkor, Philippines	ASECL - ASECL, Taiwan
VFQFPN-28 VFQFPN-32 VFQFPN-36	X	X	X

Note: X denote qualified assembly location

Table 2: Assembly Material Sets for The Existing and Alternate Assembly Locations

Material Set / Assembly	Existing Assembly	Alternate Assembly	
	ATK - Amkor, Korea	ATP - Amkor, Philippines	ASECL - ASECL, Taiwan
Die Attach	CRM1085A	CRM1085A	EN4900G
Wire	PdCu wire	PdCu wire	PdCu wire
Mold Compound	G700, G631BQF	G700, G631BQF	G700LA



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Qualification Information and Qualification Data:

Affected Packages: VFQFPN-28, VFQFPN-32, VFQFPN-36

Assembly Material: The affected package type is using ATP and ASECL standard materials shown on page 2 of this attachment.

Qual Plan & Results: Tests are in accordance with JEDEC47 recommended tests.

Qualification Vehicle: VFQFPN-36 (4 lots)

Test Description	Test Method	Test Results (Rej / SS)
* HAST - biased (130 °C/85% RH, 96 Hrs)	JESD22-A110	0/30, 0/30, 0/30, 0/30
* Temperature Cycling (-55°C to 125°C, 700 cycles)	JESD22-A104	0/30, 0/30, 0/30, 0/30
High Temperature Storage Test (150°C, 1000 hours)	JESD22-A103	0/30, 0/30, 0/30, 0/30

* Tests were subjected to Preconditioning per JESD22-A113 prior to stress test



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Affected Part Numbers

Part Number	Part Number	Part Number	Part Number
F1100NBGI	F1150NBGI8	F1200NBGI	F1241NBGI8
F1100NBGI8	F1152NBGI	F1200NBGI8	F1350NBGI
F1102NBGI	F1152NBGI8	F1240NBGI	F1350NBGI8
F1102NBGI8	F1162NBGI	F1240NBGI8	F1370NBGI
F1150NBGI	F1162NBGI8	F1241NBGI	F1370NBGI8